NUMERICAL MODELING OF RESISTIVE SWITCHING IN RRAM DEVICE.

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### Research motivation: Bipolar resistive switching



# Statement of goal

- Develop a numerical model of bipolar filamentary RRAM operation based on physical theory,
  - independent of microscopic structure details
  - RRAM characteristics described via material parameters
  - generates device I-V characteristics

## Outline

#### Thermodynamics theory of filament switching

- Mechanism of filamentary switching
- Physics behind switching
- Three Phase System
- Free energy
- Numerical Modeling
- •Partial Differential Equations
- Material Parameters and Boundary Conditions
- Workflow
- Free energy and I-V Characteristics

## Mechanism of filamentary switching



## Physics Behind Switching: current carrying CF charges and produces radial field



Field Induced Nucleation then shunting ~1V/10nm = 10<sup>8</sup> V/m

CF charging polarizes insulating host matrix Reversing Polarity charges CF unfavorable to the inherited polarization of the host Charged CF produces a strong lateral field in its vicinity opposite to the host polarization, then dissolves

Note1: CF has finite capacitance Note2: wire charging effect (due to Weber, 1852) – overlooked in RRAM community

#### Phase Transformations: thermodynamic analysis is possible due to fast thermalization, minimum of three phases required to describe IV



# Thermal and Electric energy driven phase transformation

Free Energy = Thermal + Electrostatic + Phase transition (Surface & Volume)

• The free energy of the ON state,

$$F = \int \rho C_P \delta T dx^3 + \frac{1}{2} \int \epsilon |E|^2 dx^3 + 2\pi r h \sigma + \pi r^2 h \delta \mu_1$$

• The free energy of the OFF state,

$$F = \int \rho C_P \delta T dx^3 + \frac{1}{2} \int \epsilon |E|^2 dx^3 + 2\pi r l\sigma + \pi r^2 l \delta \mu_2$$

 $\rho$  is material density  $C_P$  is specific heat capacity at constant pressure  $\epsilon$  is the permittivity  $\sigma$  is the interfacial energy  $\delta \mu_1, \delta \mu_2$  is the difference in the chemical potential between insulating and unstable conducting phase, and metastable and unstable conducting phase

- Equations to solve
  - Maxwell equation : Electric field distribution
  - Fourier Law : Temperature distribution



*r* varies from 1nm to device radius for a fixed Source voltage



*l* varies from 0.5nm to *h* for fixed *r* and for a fixed source voltage

## PDE Solver: COMSOL Multiphysics<sup>®</sup>

- COMSOL uses finite element method to solve PDEs and has an excellent graphical user interface
- Solves following PDE to calculate the field and temperature distributions

Electrical CurrentsHeat Transfer in SolidsMultiphysics $\vec{\nabla}.\vec{J} = 0$  $-k\vec{\nabla}.\vec{\nabla}T = Q_s$  $Q_S = \vec{J}.\vec{E}$  $\vec{J} = \sigma_c \vec{E}$  $\vec{E} = -\vec{\nabla}V$  $\vec{V}$ 

• COMSOL also performs the necessary integration for free energy

## Material parameters and Boundary Conditions

Table.1. Material Parameters					
Material	к [W/(Km)]	σ <sub>c</sub> [S/m]	C <sub>P</sub> [J/(kgK)]	3	ρ[kg/m³]
TiN	11.9	106	545.33	-106	5.22×10 <sup>3</sup>
HfO <sub>2</sub>	0.5	10+	120	25	10×10 <sup>3</sup>
HfO <sub>2-x</sub>	0.65	2×10 <sup>4</sup>	140*	-106*	12×10 <sup>3*</sup>
Hf	23	5×10 <sup>6</sup>	144	-106	13.3×10 <sup>3</sup>
SiO <sub>2</sub>	1.38	10-14	703	3.9	2.2×10 <sup>3</sup>
Air	0.015	5×10-15	1000	1	1.225

\*Assumed values, lies in between Hf and  $HfO_2$ 

#### Table.2. Various Parameters

Parameters	Value		
σ	0.01 [J/m <sup>2</sup> ]		
δμ	3×10 <sup>9</sup> [J/m <sup>3</sup> ]		
$R_L$	15 kΩ		
TBR HfO <sub>2</sub>	3[m <sup>2</sup> K/GW]		
TBR TiN	5[m <sup>2</sup> K/GW]		

Additional Boundary Condition

- Thermal Boundary Resistance (*Thin Layer*)
- Heat lost by Radiation (*Diffusive Surface*)



#### Work Flow between MATLAB<sup>®</sup> scripts: MATLAB talks to COMSOL Multiphysics<sup>®</sup> via LiveLink<sup>™</sup> to MATLAB<sup>®</sup>, utilized to find minimum in Free Energy



#### Free Energy Plots: system evolves through minimum energy points



## Simulated I-V Characteristics: corresponds to the stable radius and gap lengths



#### **CONCLUSIONS:**

- COMSOL/MATLAB model verifies thermodynamic model
- Discrepancy in  $V_{SET}$  and  $I_{R,SAT}$  values
  - Optimization of material parameters
  - Further refinement of filament description
- Modeling full I-V characteristics in progress

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